

Notice of References Cited	Application/Control No. 10/084,400	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Veronica F. Faison	Art Unit 1755	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,851,274 A	12-1998	Lin, John Wei-Ping	106/31.43
	B	US-5,833,744 A	11-1998	Breton et al.	106/31.59
	C	US-6,231,653 B1	05-2001	Lavery et al.	106/31.36
	D	US-6,379,441 B1	04-2002	Kanaya et al.	106/31.49
	E	US-5,973,026 A	10-1999	Burns et al.	523/160
	F	US-5,997,623 A	12-1999	Lin, John Wei-Ping	106/31.58
	G	US-6,231,655 B1	05-2001	Marritt, William Alan	106/31.58
	H	US-6,306,204 B1	10-2001	Lin, John Wei-Ping	106/31.43
	I	US-6,498,222 B1	12-2002	Kitamura et al.	526/307.2
	J	US-6,500,248 B1	12-2002	Hayashi, Hiroko	106/31.86
	K	US-2002/0121220 A1	09-2002	Lin, John Wei-Ping	106/31.27
	L	US-2001/0032566 A1	10-2001	Yatake, Masahiro	106/31.58
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.